

**A scalable static test set compaction method for sequential circuits**

**Aleksejev, Igor; Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes** Proceedings of the 9th IEEE Latin-American Test Workshop : LATW2008 : February 17-20, 2008, Puebla, Mexico 2008 / p. 87-92 : ill

**Built-in self diagnosis with multiple signature analyzers in digital systems**

**Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan** Proceedings of the 9th IEEE Latin-American Test Workshop : LATW2008 : February 17-20, 2008, Puebla, Mexico 2008 / p. 29-34 : ill

**PSL assertion checking with temporally extended high-level decision diagrams**

**Jenihhin, Maksim; Raik, Jaan; Tšepurov, Anton; Ubar, Raimund-Johannes** Proceedings of the 9th IEEE Latin-American Test Workshop : LATW2008 : February 17-20, 2008, Puebla, Mexico 2008 / p. 49-54 : ill  
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